

IMPROVED CHARGED PARTICLE DETECTOR

ABSTRACT

The present invention relates generally to components of scientific analytical equipment, and to complete items of analytic equipment. More particularly, the invention relates to apparatus and methods useful for detecting an ion in mass spectrometry applications. The apparatus may comprise an electron multiplier having a high sensitivity and low sensitivity sections, or the combination of an electron multiplier with a separately powered conversion dynode (and particularly a high energy conversion dynode), or the combination of a conversion dynode that is physically incorporated within or about an electron multiplier.

[FIG. 2A]